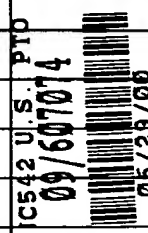


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LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)				Applicants: John C. Fluke, Joel M. Yarborough			
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Examiner Initials		Document No.	Date	Name	Class	Subclass	Filing Date if Appropriate
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